

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10517214	MAEKAWA ET AL.
	Examiner	Art Unit
	Jaisle, Cecilia M	1624

SEARCHED

Class	Subclass	Date	Examiner
514	403, 404	8/12/2009	Cecilia Jaisle
548	373.1, 375.1	8/12/2009	Cecilia Jaisle
546	275.4, 276.4	8/12/2009	C. Jaisle
544	238	8/12/2009	CJ

SEARCH NOTES

Search Notes	Date	Examiner
STN and Inventor Names searched by STIC	10/10/2007	Cecilia Jaisle

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
514	403, 404	8/12/2009	C. Jaisle
548	373.1, 375.1	8/12/2009	C. Jaisle
546	275.4, 276.4	8/12/2009	CJ
544	238	8/12/2009	CJ

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